

Notice of References Cited	Application/Control No. 10/645,209		Applicant(s)/Patent Under Reexamination CHAN ET AL.	
	Examiner Ramesh B. Patel		Art Unit 2121	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-5,784,273 A	07-1998	Madhavan, Poovanpilli G.	700/71
X	B	US-6,004,017 A	12-1999	Madhavan, Poovanpilli G.	700/71
X	C	US-6,738,954 B1	05-2004	Allen et al.	716/4
X	D	US-2001/0032025 A1	10-2001	Lenz et al.	700/28
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Advanced analysis of dynamic neural control advisories for process optimization and parts maintenance;Card, J.P.; Chan, W.T.; Cao, A.; Martin, W.; Morgan, J.; Advanced Semiconductor Manufacturing Conference and Workshop, 2003 IEEE/SEMI , 31 March-1 April.
	V	Utilization of the saturation effect on a DC motor drive with a fuzzy controller; Lee, C.K.; Chan, W.T.; Industrial Automation and Control: Emerging Technologies, 1995., International IEEE/IAS Conference on , 22-27 May 1995 , Pages:342 - 349.
	W	Precast production scheduling with genetic algorithms; Chan, W.T.; Hu, H.; Evolutionary Computation, 2000. Proceedings of the 2000 Congress on ,Volume: 2 , 16-19 July 2000, Pages:1087 - 1094 vol.2.
	X	Predicting failure modes to improve reliability; Reid, J.M.; Reliability and Maintainability Symposium, 1990. Proceedings., Annual , 23-25 Jan. 1990,Pages:497 - 500.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.